77126 SEARCH REQUEST FORM Scientific and Technical Information Center - EIC2800 This is an experimental format -- Please give suggestions or comments to Jeff Harrison, CP4-9C18, 306-5429. _ Serial # 09/686200 Priority Application Date 10/05/02 Examiner # Phone 703. 305-4914 Room & CP4 In what format would you like your results? Paper is the default. PAPER DISK **EMAIL** If submitting more than one search, please prioritize in order of need. The EIC searcher normally will contact you before beginning a prior art search. If you would like to sit with a searcher for an interactive search, please notify one of the searchers. 10-03-02A11:35 PAID Where have you searched so far on this case? Circle: **USPT DWPI** EPO Abs JPO Abs IBM TDB Other: What relevant art have you found so far? Please attach pertinent citations or Information Disclosure Statements. What types of references would you like? Please checkmark: Primary Refs Nonpatent Literature ____ Secondary Refs Foreign Patents ____ Teaching Refs ____ What is the topic, such as the novelty, motivation, utility, or other specific facets defining the desired focus of this search? Please include the concepts, synonyms, keywords, acronyms, registry numbers, definitions, structures, strategies, and anything else that helps to describe the topic. Please attach a copy of the abstract and pertinent claims. Vendors Type of Search Staff Use Only Structure (#)_ Searcher: Dialog_ Bibliographic Searcher Phone: Searcher Location: STIC-EIC2800, CP4-9C18 Ouestel/Orbit Litigation Lexis-Nexis_ Fulltext Date Searcher Picked Up: _____ WWW/Internet_ Patent Family_ Date Completed:

Other

Other_

Searcher Prep/Rev Time:

Online Time:

```
Selected file: PLUSPAT
  Search statement
                     2
?us5818249/pn
  ** SS 2: Results 1
  Search statement
?prt fu legalall max
  1/1 PLUSPAT - (C) QUESTEL-ORBIT- image
  CPIM (C) Questel-Orbit
  PN - US5818249 A 19981006 [US5818249]
     - (A) Probe card having groups of probe needles in a probing test
       apparatus for testing semiconductor integrated circuits
     - (A) TOKYO SHIBAURA ELECTRIC CO (JP)
  IN - (A) MOMOHARA TOMOMI (JP)
 AP - US71866096 19960923 [1996US-0718660]
  PR - JP24953195 19950927 [1995JP-0249531]
     - (A) G01R-001/073 G01R-031/02
 EC - G01R-001/073B4
 ICO - S01R-031/28E11
 PCL - ORIGINAL (O) : 324762000
     - Basic
 CT - US4523144; US4799009; US4994735; US5012187; US5148103; US5525912;
       US5623214; US5642054
 STG - (A) United States patent
     - A probe card which can help to enhance the productivity of
       semiconductor integrated circuits manufacturing and to reduce the
       manufacturing cost thereof, and a method of probe-testing
       semiconductor integrated circuits by using the probe card. The probe
       card is designed to test semiconductor integrated circuits formed on a
       semiconductor wafer and arranged in rows and columns. It has groups of
       probe needles provided to contact semiconductor integrated circuits
       arranged in two columns and at least two rows. The card receives a
       test signal from a test device and supplies the test signal
       simultaneously to these semiconductor integrated circuits arranged in
       two columns and at least tow rows, through the groups of probe
       needles. It receives response signals simultaneously from the
       semiconductor integrated circuits through the groups of probe needles
       and then supplies the response signals to the tester.
 1/1 LGST - (C) LEGSTAT
 PN - US 5818249 [US5818249]
     - US 718660/96 19960923 [1996US-0718660]
     - US-P
 ACT - 19960923 US/AE-A
       APPLICATION DATA (PATENT)
       {US 718660/96 19960923 [1996US-0718660]}
     - 19960923 US/AS02
       ASSIGNMENT OF ASSIGNOR'S INTEREST
       KABUSHIKI KAISHA TOSHIBA SAIWAI-KU 72 HORIKAWA-CHO KAWASAKI-SHI, JAPAN
        * MOMOHARA, TOMOMI : 19960912
```

- 19981006 US/A

PATENT

10/3/02 US 5,818,249

05 5,818,249

- 20001226 US/RF REISSUE APPLICATION FILED

20001005

- 20010206 US/RF REISSUE APPLICATION FILED 20001005

- 20020507 US/RF REISSUE APPLICATION FILED 20001005

UP - 2002-20

1/1 CRXX - (C) CLAIMS/RRX

AN - 3051183

PN - 5,818,249 D 19981006 [US5818249]

PA - Toshiba Corp JP PT - E (Electrical)

ACT - 20001005 REISSUE REQUESTED
ISSUE DATE OF O.G.: 20001226
REISSUE REQUEST NUMBER: 09/686200

EXAMINATION GROUP RESPONSIBLE FOR REISSUEPROCESS: 2858

09/686200

Reissue Patent Number:

- 20001005 REISSUE REQUESTED ISSUE DATE OF O.G.: 20010206 REISSUE REQUEST NUMBER: 09/686200 EXAMINATION GROUP RESPONSIBLE FOR REISSUEPROCESS: 2858

Reissue Patent Number:

- 20001005 REISSUE REQUESTED ISSUE DATE OF O.G.: 20020507 REISSUE REQUEST NUMBER: 09/686200 EXAMINATION GROUP RESPONSIBLE FOR REISSUEPROCESS: 2858

Reissue Patent Number:

UP - 2000-52 UACT- 2002-05-07

1/3 PAST - (C) Thomson Derwent

AN - 200219-001721

PN - 5818249 A [US5818249]

DT - A (UTILITY)
OG - 2002-05-07

CO - REA

ACT - REISSUE APPLICATION FILED SH - REISSUE APPLICATION FILED

2/3 PAST - (C) Thomson Derwent

AN - 200106-001128

PN - 5818249 A [US5818249]

DT - A (UTILITY)
OG - 2001-02-06

```
10/3/02
                      US 5,818,249
                                              09/686200
  CO - REA
  ACT - REISSUE APPLICATION FILED
  SH - REISSUE APPLICATION FILED
  3/3 PAST - (C) Thomson Derwent
  AN - 200052-001230
  PN - 5818249 A [US5818249]
  DT - A (UTILITY)
  OG - 2000-12-26
  CO - REA
 ACT - REISSUE APPLICATION FILED
  SH - REISSUE APPLICATION FILED
  Search statement
                      3
?file inpadoc
  Selected file: INPADOC
  Search statement
                      2
?fam us5818249/pn
  1 Patent Groups
  ** SS 2: Results 4
  Search statement
                      3
?famstate nonstop
  1/4 INPADOC - (C) INPADOC
  PN - JP 3135825 B2 20010219 [JP3135825]
     - MOMOHARA TOMOYOSHI
     - TOKYO SHIBAURA ELECTRIC CO
 AP - JP 249531/95-A 19950927 [1995JP-0249531]
PR - JP 249531/95-A 19950927 [1995JP-0249531]
  IC - H01L-021/66
  2/4 INPADOC - (C) INPADOC
     - JP 9092694 A2 19970404 [JP09092694]
     - PROBE CARD AND PROBE TEST METHOD FOR SEMICONDUCTOR INTEGRATED CIRCUIT
        USING THE PROBE CARD
     - MOMOHARA TOMOYOSHI
     - TOKYO SHIBAURA ELECTRIC CO
 AP - JP 249531/95-A 19950927 [1995JP-0249531]
PR - JP 249531/95-A 19950927 [1995JP-0249531]
  IC - H01L-021/66; G01R-001/073; G01R-031/26
  3/4 INPADOC - (C) INPADOC
  PN - TW 409335 B 20001021 [TW-409335]
     - PROBE CARD AND PROBE TEST METHOD FOR SEMICONDUCTOR INTEGRATED CIRCUIT
        USING THE PROBE CARD
  IN - MOMOHARA TOMOMI [JP]
```

10/3/02

US 5,818,249

09/686200

```
PA - TOKYO SHIBAURA ELECTRIC CO [JP]
```

AP - TW 85112468/96-A 19961012 [1996TW-0112468] PR - JP 249531/95-A 19950927 [1995JP-0249531]

IC - H01L-021/66

4/4 INPADOC - (C) INPADOC

PN - US 5818249 A 19981006 [US5818249]

TI - PROBE CARD HAVING GROUPS OF PROBE NEEDLES IN A PROBING TEST APPARATUS FOR TESTING SEMICONDUCTOR INTEGRATED CIRCUITS

IN - MOMOHARA TOMOMI [JP]

PA - TOKYO SHIBAURA ELECTRIC CO [JP]

AP - US 718660/96-A 19960923 [1996US-0718660] PR - JP 249531/95-A 19950927 [1995JP-0249531]

IC - G01R-031/02; G01R-001/073

1/1 LEGALI - (C) LEGSTAT

PN - US 5818249 [US5818249]

AP - US 718660/96 19960923 [1996US-0718660]

DT - US-P

ACTE- 19960923 US/AE-A

APPLICATION DATA (PATENT)

{US 718660/96 19960923 [1996US-0718660]}

- 19960923 US/AS02

ASSIGNMENT OF ASSIGNOR'S INTEREST

KABUSHIKI KAISHA TOSHIBA SAIWAI-KU 72 HORIKAWA-CHO KAWASAKI-SHI, JAPAN * MOMOHARA, TOMOMI : 19960912

- 19981006 US/A

PATENT

- 20001226 US/RF

REISSUE APPLICATION FILED

20001005

- 20010206 US/RF

REISSUE APPLICATION FILED

20001005

- 20020507 US/RF

REISSUE APPLICATION FILED

20001005

UP - 2002-20



Source: Legal > Area of Law - By Topic > Patent Law > Patents > U.S. Patents > Utility Patents (i)

Terms: patno=5818249 (Edit Search)

08718660 () 5818249 October 6, 1998

UNITED STATES PATENT AND TRADEMARK OFFICE GRANTED PATENT 5818249

Access PDF of Official Patent. (Note: Cost incurred in a later step)

The Adobe Acrobat Reader must be installed on your computer to access Official Patent text. If you do not have this FREE reader, you can download it now from www.adobe.com.

Link to Claims Section S GET 1st DRAWING SHEET OF 11

October 6, 1998

Probe card having groups of probe needles in a probing test apparatus for testing semiconductor integrated circuits

REISSUE: October 5, 2000 - Reissue Application filed Oct. 5, 2000 (O.G. Feb. 6, 2001) Ex. Gp.: 2858; Re. S.N. 09/686,200Reissue Application filed Oct. 5, 2000 (O.G. Dec. 26, 2000) Ex. Gp.: 2858; Re. S.N. 09/686,200February 6, 2001; October 5, 2000 - Reissue Application filed Ex. Gp.: 2858; Re. S.N. 09/686,200May 7, 2002

INVENTOR: Momohara, Tomomi, Yokohama, JPX

APPL-NO: 08718660 ()

FILED-DATE: September 23, 1996

GRANTED-DATE: October 6, 1998

PRIORITY: September 27, 1995 - 7-249531, Japan (JP)

ASSIGNEE-AT-ISSUE: Kabushiki Kaisha Toshiba, Tokyo, JPX

ASSIGNEE-AFTER-ISSUE: September 23, 1996 - ASSIGNMENT OF ASSIGNOR'S INTEREST (SEE DOCUMENT FOR DETAILS)., KABUSHIKI KAISHA TOSHIBA SAIWAI-KU 72

HORIKAWA-CHO KAWASAKI-SHI, JAPAN,, Reel and Frame Number: 008237/0461

LEGAL-REP: Loeb & Loeb LLP

PUB-TYPE: October 6, 1998 - Utility Patent having no previously published pre-grant

publication (A)

PUB-COUNTRY: United States (US)

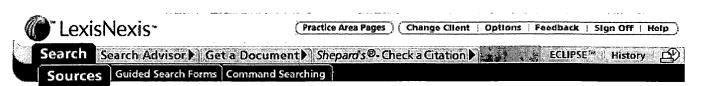
US-MAIN-CL: 324#762

SEARCH-FLD: 324##762, 324##731, 324##758, 324##760, 324##754, 437##8

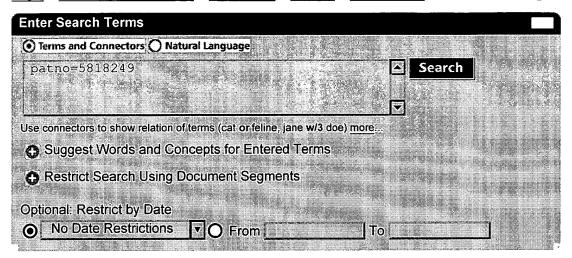
IPC-MAIN-CL: G 01R031#2

IPC ADDL CL: G 01R001#73

PRIM-EXMR: Karlsen, Ernest F.



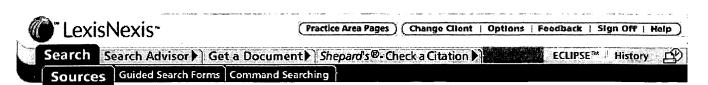
Legal > Area of Law - By Topic > Patent Law > Patents > U.S. Patents > Utility Patents (1)



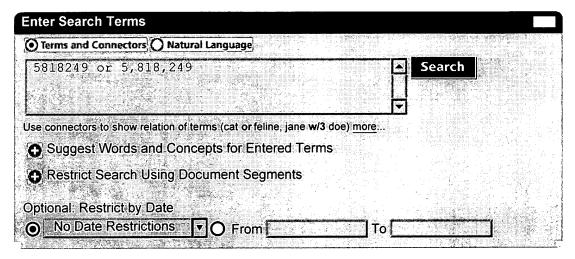
Search | Search Advisor | Get a Document | Shepard's ® - Check a Citation

Eclipse ™ | History | Delivery Manager | Practice Area Pages | Change Client | Options | Feedback | Signoff | Help

About LexisNexis | Terms and Conditions



<u>Legal > Area of Law - By Topic > Patent Law > Multi-Source Groups > Patent Cases from Federal Courts and Administrative Materials (i)</u>



Search | Search Advisor | Get a Document | Shepard's ® - Check a Citation

Eclipse ™ | History | Delivery Manager | Practice Area Pages | Change Client | Options | Feedback | Signoff | Help

About LexisNexis | Terms and Conditions





No documents were found for your search (5818249 or 5,818,249). Please edit your search and try again. You may want to try one or more of the following:

- · Check for spelling errors.
- Remove some search terms.
- Use more common search terms.
 If applicable, look for all dates:

Edit Search

About LexisNexis | Terms and Conditions

"LexisNexis"

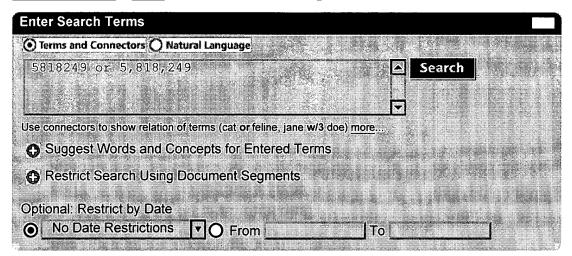




Search Advisor (Get a Document) Shepard's @-Check a Citation (Citation) ECLIPSE** History

News & Business > News > News Group File, All (i)

Sources Guided Search Forms Command Searching



Search | Search Advisor | Get a Document | Shepard's ® - Check a Citation

Eclipse ™ | History | Delivery Manager | Practice Area Pages | Change Client | Options | Feedback | Signoff | Help

About LexisNexis | Terms and Conditions





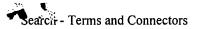
No Documents Found

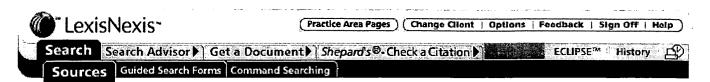
No documents were found for your search (5818249 or 5(318,249)). Please edit your search and try again. You may want to try one or more of the following:

- Check for spelling errors.Remove some search terms.
- Use more common search terms.
- · If applicable, look for all dates.

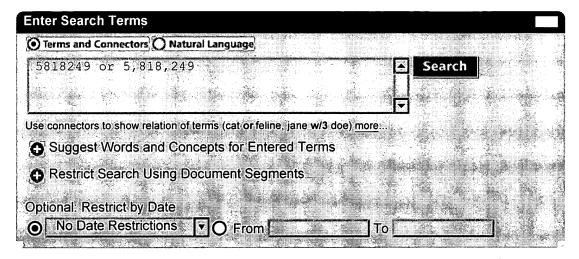
Edit Search

About LexisNexis | Terms and Conditions





<u>Legal > Area of Law - By Topic > Patent Law > Legal News > Patent, Trademark & Copyright Periodicals, Combined (i)</u>



Search | Search Advisor | Get a Document | Shepard's ® - Check a Citation | Eclipse ™ | History | Delivery Manager | Practice Area Pages | Change Client | Options | Feedback | Signoff | Help About LexisNexis | Terms and Conditions







No documents were found for your search (5818249 or 5,818,249) Please edit your search and try again. You may want to try one or more of the following:

- Check for spelling errors.
 Remove some search terms.
 Use more common search terms.
 If applicable, look for all dates.

Edit Search

About LexisNexis | Terms and Conditions